

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	Mehrdad Nikoonahad et al.		
Title:	Optical System For Measuring Samples Using Short Wavelength Radiation		
Application No.:	10/718,126	Filing Date:	November 19, 2003
Examiner:	Pham, Hoa Q.	Group Art Unit:	2886
Docket No.:	TNCR.197US1	Conf. No.:	9108

Mail Stop RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

REQUEST FOR CONTINUED EXAMINATION (RCE)

Dear Sir:

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application. Please consider the Response to Office Action and Petition for Extension of Time, which are being filed herewith.

The RCE fee of \$790.00 required under 37 C.F.R. § 1.17(e) has been authorized via EFS to Deposit Account 04-0258. The Commissioner is hereby authorized to charge any additional fees, which may be required, or credit any overpayment to Deposit Account 04-0258. Please contact the undersigned with any questions concerning this request or the above-identified patent application.

FILED VIA EFS

Respectfully submitted,



James S. Hsue
Reg. No. 29,545

09/18/2007

Date

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